

Notice of References Cited	Application/Control No. 09/675,637	Applicant(s)/Patent Under Reexamination YAMANISHI ET AL.	
	Examiner Ayal I. Sharon	Art Unit 2123	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0111769 A1	08-2002	TAKEUCHI et al.	702/181
	B	US-2004/0167893 A1	08-2004	Matsunaga et al.	707/006
	C	US-2005/0222806 A1	10-2005	Golobrodsky, Oleg	702/179
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Kou, Yufeng et al. "Survey of Fraud Detection Techniques." 2004 IEEE Int'l Conf. on Networking, Sensing and Control. 2004. Vol.2, pp.749-754.
	V	Lu, Chang-Tien et al. "Exploiting Efficient Data Mining Techniques to Enhance Intrusion Detection Systems." 2005 IEEE Int'l Conf. on Information Reuse and Integration. Aug. 15-17, 2005. pp.512-517.
	W	"Outlier Detection: nagdmc_bacon." http://www.nag-j.co.jp/pdf/nagdmc_bacon.pdf . Printed 10/6/05
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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